

### REMARKS

This application has been reviewed in light of the Office Action dated May 16, 2007. Claims 6-10, 21, 22, 26, 27, and 35-45 are presented for examination, of which Claims 6, 8, and 37 are in independent form. Claims 6-10, 21, 22, 26, 27 have been amended, and Claims 35-45 have been added to provide Applicants with a more complete scope of protection. Favorable reconsideration is requested.

Applicants gratefully acknowledge the indication that Claims 8-10, 21, and 22 include allowable subject matter that would be allowable if rewritten in proper independent form. Claim 8 has been rewritten as an independent claim. Therefore, it is respectfully submitted that Claim 8 as well as Claims 21, 22, 35, and 36 dependent therefrom are in condition for allowance. However, for the reasons discussed below, Applicants respectfully decline to rewrite Claims 9 and 10 as independent claims at the present time, because Claim 6, from which these claims depend, is believed to be allowable.

The Office Action states that Claims 6 and 26 are rejected under 35 U.S.C. § 112, second paragraph, as being indefinite. Applicants have carefully reviewed and amended these claims, as deemed necessary, with special attention to the points raised in section 3 of the Office Action. In particular, the term “high-speed electrical component” has been changed to --electrical component--, as apparently suggested in the Office Action. This change should not be construed as an indication that the term “electrical component” does not include components that are high-speed; instead, this change has been made for purposes of clarity and to broaden the scope of the claims to encompass components of various speeds. In view of the above, withdrawal of the rejections under 35 U.S.C. § 112, second paragraph, is respectfully requested.

The Office Action states that Claims 6, 7, 26, and 27 are rejected under 35 U.S.C. § 103(a) as being unpatentable over U.S. Patent No. 4,775,640 (Chan) in view of U.S. Patent No. 4,891,577 (Ishikawa). Applicants submit that independent Claim 6 as well as the claims dependent therefrom are patentably distinct from the cited prior art for at least the following reasons.

The aspect of the present invention set forth in Claim 6 is directed to a method for testing an optical component. The method includes providing a golden electrical component that generates signals having known characteristics. The method also includes removably connecting the optical component to a high-frequency probe, and removably connecting the high-frequency probe to the golden electrical component. The method further includes transmitting an electrical signal from the golden electrical component to the optical component, and identifying a response by the optical component to the electrical signal.

Among other important features of Claim 6 are removably connecting the optical component to a high-frequency probe, and removably connecting the high-frequency probe to the golden electrical component. Because the optical component and the high-frequency probe are removably connected, the process of testing an optical component can be repeated easily by disconnecting the optical component and connecting a different optical component in its place without the need to break or create non-removable connections, such as, for example, solder joints.

Chan relates to a system for testing LEDs that are included on a semiconductor wafer. In section 5 of the Office Action, it is alleged that “the optical equipment (18) of Chan is a golden high-speed component, because it requires producing the good/steady signals within the specific range for testing the device under test (DUT).”

According to Chan:

The system is controlled by a computer 15, which controls prober controller 16, switching matrix 17, and opto-electronic equipment 18. Contact to all of the LEDs of the wafer is made by a lead 20 to the gold plated plate 12. Individual diodes of the wafer are tested by applying a current to lead 20, through a selected LED by way of a test probe 21, which biases the LED to cause it to emit light. The emitted light is collected by an optical fiber 22 and transmitted to an optical switch 23. The switch transmits the light to the opto-electronic equipment 18 which analyzes it to determine peak emission wavelength and spectral width. The bias current voltage and power are also measured and this information is transmitted via switching matrix 17 to the computer 15. . . .

(Chan at col. 2, line 60, to col. 3, line 6). Apparently, during testing of a diode, a probe is temporarily connected to the diode during transmission of a current to the diode. However, as Applicants understand the Chan system, the probe is not *removably* connected to both an optical component and a golden electrical component. This limits the Chan system to testing devices with only a single optoelectronic equipment-probe combination, without the ability to removably connect other optoelectronic equipment to testing other devices. No other description of the opto-electronic equipment 18 was found in Chan.

Ishikawa relates to a system for measuring noise characteristics, and was cited in the Office Action for disclosing the use of a high-frequency probe.

Nothing has been found in Chan or in Ishikawa that teaches or suggests removably connecting an optical component to a high-frequency probe, and removably connecting the high-frequency probe to a golden electrical component, as claimed in Claim 6.

In view of the above, Applicants submit that any permissible combination of Chan and Ishikawa would fail to disclose or suggest all the features of Claim 6. Accordingly, Claim 6 is believed to be clearly allowable over the cited references and therefore withdrawal of the rejection under 35 U.S.C. § 103(a) is respectfully requested.

In regard to new independent Claim 37, this claim includes many features that are similar to those of Claim 6. For example, Claim 37 is directed to a method for testing an optical component. The method includes providing a golden printed circuit board including golden components that generate signals having known characteristics. Also, the method includes removably connecting the optical component to a high-frequency probe, and removably connecting the high-frequency probe to the golden printed circuit board. The method also includes transmitting an electrical signal from the golden printed circuit board to the optical component, and identifying a response by the optical component to the electrical signal. Therefore, it is respectfully submitted that Claim 37 is patentable over the cited prior art for at least the reasons discussed above in connection with Claim 6.

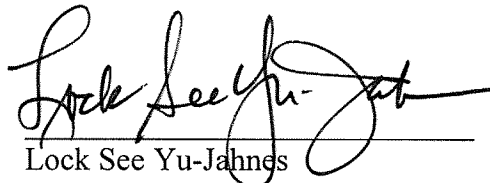
The other claims in this application are each dependent from one or another of the independent claims discussed above and therefore are believed to be patentable for at least the reasons discussed above. Because each dependent claim also is deemed to define an additional aspect of the invention, individual consideration or reconsideration, as the case may be, of the patentability of each claim on its own merits is respectfully requested.

In view of the foregoing amendments and remarks, Applicants respectfully request favorable reconsideration and early passage to issue of the present application.

CONCLUSION

Applicants' undersigned attorney may be reached in our New York Office by telephone at (212) 218-2100. All correspondence should continue to be directed to our address listed below.

Respectfully submitted,

A handwritten signature in black ink, appearing to read "Lock See Yu-Jahnes", written over a horizontal line.

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